

FORM PTO-892 (REV. 2-92)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		SERIAL NO. 08/416100	GROUP/ART UNIT 2212	ATTACHMENT TO PAPER NUMBER 3	
NOTICE OF REFERENCES CITED				APPLICANT(S) Prater et al.			
U.S. PATENT DOCUMENTS							
•	DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE	
A	3013467	12/61	Minsky	356	432	—	
B	4935634	6/90	Hansma et al.	250	306	—	
C	5117466	5/92	Buicon et al.	382	6	—	
D	5127730	7/92	Brelja et al.	356	318	—	
E	5164791	11/92	Kubo et al.	250	306	—	
F	5172002	12/92	Marshall	250	306	—	
G	5206702	4/93	Kato et al.	250	306	—	
H	5231286	7/93	Kajimura et al.	250	306	—	
I	5260824	11/93	Okada et al.	250	306	19 April '90	
J	5291775	3/94	Gamble et al.	73	105	04 March '92	
K	5298975	3/94	Khoury et al.	73	105	27 Sept. '91	
FOREIGN PATENT DOCUMENTS							
•	DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUB-CLASS	PERTINENT SHTS. DWG.
L	698194	11/64	Canada	Dreyfus	73	105	PP. SPEC.
M							
N							
O							
P							
Q							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
R	Hipp et al., "A Stand-Alone Scanning Force and Friction Microscope", Ultramicroscopy, 42-44, 1992, pp. 1498-1503.						
S	Baselt et al., "Scanned-Cantilever Atomic Force Microscope", Rev. Sci. Instrum., 64(4), April 1993, pp. 908-911.						
T	Clark et al., "A High Performance Scanning Force Microscope Head Design", Rev. Sci. Instrum., 64(4), April 1993, pp. 904-907.						
U							
EXAMINER		DATE					
		13 July 1995					
<p>* A copy of this reference is not being furnished with this office action. (See Manual of Patent Examining Procedure, section 707.05 (a).)</p>							

Page 2 of 2

FORM PTO-892 (REV. 2-92)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		SERIAL NO. <i>08/416100</i>	GROUP/ART. UNIT <i>2212</i>	ATTACHMENT TO PAPER NUMBER <i>3</i>		
NOTICE OF REFERENCES CITED				APPLICANT(S) <i>Prater et al.</i>				
U.S. PATENT DOCUMENTS								
	DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE		
A	<i>5388452</i>	<i>2/95</i>	<i>Harp et al.</i>	<i>73</i>	<i>105</i>	<i>15 Oct. '92</i>		
B	<i>5394741</i>	<i>3/95</i>	<i>Kajimura et al.</i>	<i>73</i>	<i>105</i>	<i>27 April '92</i>		
C	<i>5406833</i>	<i>4/95</i>	<i>Yamamoto</i>	<i>73</i>	<i>105</i>	<i>13 Aug. '93</i>		
D								
E								
F								
G								
H								
I								
J								
K								
FOREIGN PATENT DOCUMENTS								
	DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUB-CLASS	PERTINENT SHTS. DWG.	PP. SPEC.
L								
M								
N								
O								
P								
Q								
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)								
R	<i>Jung et al., "Novel Stationary-Sample Atomic Force Microscope with Beam-Tracking Lens", Electronic Letters, Vol. 29, No. 3,</i>							
S	<i>February 1993, pp. 264-266.</i>							
T	<i>Martin et al., "Atomic Force Microscope-Force Mapping and Profiling on a Sub 100-Å Scale", J. Appl. Phys., 61(10), 15 May 1987, 4723-4729.</i>							
U	<i>van der Werf et al., "Compact Stand-Alone Atomic Force Microscope", Rev. Sci. Instrum., 64(10), October 1993, pp. 2892-2897.</i>							
EXAMINER <i>David J. Hill</i>		DATE <i>13 July 1995</i>						
* A copy of this reference is not being furnished with this office action. (See Manual of Patent Examining Procedure, section 707.05 (a).)								